

Stefano Di Pascoli

List of Publications by Year in descending order

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19
papers

396
citations

1163117

8
h-index

839539

18
g-index

19
all docs

19
docs citations

19
times ranked

539
citing authors

#	ARTICLE	IF	CITATIONS
1	Variability-aware design of a bandgap voltage reference with 0.18% standard deviation and 68ÅnW power consumption. International Journal of Circuit Theory and Applications, 2018, 46, 1985-1999.	2.0	5
2	Low-Power Wearable ECG Monitoring System for Multiple-Patient Remote Monitoring. IEEE Sensors Journal, 2016, 16, 5452-5462.	4.7	184
3	Derailment Detection and Data Collection in Freight Trains, Based on a Wireless Sensor Network. IEEE Transactions on Instrumentation and Measurement, 2016, 65, 1977-1987.	4.7	21
4	Design of a nanopower current reference with reduced process variability. Analog Integrated Circuits and Signal Processing, 2013, 77, 45-53.	1.4	6
5	Design and Implementation of a Wireless In-Ovo EEG/EMG Recorder. IEEE Transactions on Biomedical Circuits and Systems, 2013, 7, 832-840.	4.0	9
6	Low-voltage nanopower clock generator for RFID applications. Microelectronics Journal, 2008, 39, 1736-1739.	2.0	4
7	Noise and reliability in simulated thin metal films. Microelectronics Reliability, 2008, 48, 1015-1020.	1.7	2
8	Fundamental limits to power consumption of LC subthreshold oscillators. Electronics Letters, 2008, 44, 13.	1.0	4
9	Three-Dimensional Simulations of Quantum Confinement and Random Dopants Effects in Nanoscale nMOSFETs. Journal of Computational and Theoretical Nanoscience, 2008, 5, 1115-1119.	0.4	3
10	Base coupled differential amplifier: a new topology for RF integrated LNA. International Journal of Circuit Theory and Applications, 2003, 31, 351-360.	2.0	5
11	A comparison of some circuit schemes for semi-reversible adiabatic logic. International Journal of Electronics, 2002, 89, 147-158.	1.4	10
12	Four-phase power clock generator for adiabatic logic circuits. Electronics Letters, 2002, 38, 689.	1.0	20
13	Simulation of failure time distributions of metal lines under electromigration. Microelectronics Reliability, 2002, 42, 1469-1472.	1.7	0
14	Natural gas, cars and the environment. A (relatively) "clean"™ and cheap fuel looking for users. Ecological Economics, 2001, 38, 179-189.	5.7	63
15	Simulation of electromigration noise in polycrystalline metal stripes. Microelectronics Reliability, 2000, 40, 1955-1958.	1.7	1
16	Simple model for positive-feedback adiabatic logic power consumption estimation. Electronics Letters, 2000, 36, 116.	1.0	29
17	Monte Carlo simulation of electromigration in polycrystalline metal stripes. Semiconductor Science and Technology, 2000, 15, 608-612.	2.0	5
18	Thermal analysis of insulated metal substrates for automotive electronic assemblies. Microelectronics Journal, 1999, 30, 1129-1135.	2.0	18

#	ARTICLE	IF	CITATIONS
19	Temperature coefficient of resistance fluctuations during electromigration in Al lines. Microelectronics Reliability, 1997, 37, 77-85.	1.7	7